

Notice of References Cited	Application/Control No. 10/582,788		Applicant(s)/Patent Under Reexamination ONO ET AL.	
	Examiner John L. Goff		Art Unit 1791	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,018,559	04-1977	Retzsch, Clinton E.	8/94.2
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	U	Machine translation of JP 2001348786 date unknown
	V	Machine translation of JP 06106682 date unknown
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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